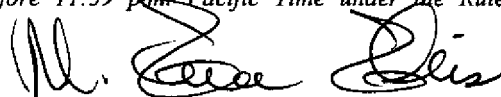


PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

I hereby certify that this correspondence is being electronically filed with the United States Patent and Trademark Office on July 24, 2007 at or before 11:59 p.m. Pacific Time under the Rules of 37 CFR § 1.8.



M. Ena Ellis

Appl No. : 10/674,654 Confirmation No. 4784
Applicant : Akio Ishikawa
Filed : September 29, 2003
Title : IMAGE DEFECT INSPECTION METHOD, IMAGE DEFECT
INSPECTION APPARATUS AND APPEARANCE INSPECTION
APPARATUS
TC/A.U. : 2624
Examiner : John B. Stregé
Docket No. : 51272/A400
Customer No. : 23363

RESPONSE

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Post Office Box 7068
Pasadena, CA 91109-7068
July 24, 2007

Commissioner:

In response to the Office action of April 24, 2007, please consider the remarks as follows:

Listing of the claims begins on page 2 of this paper.

Remarks/Arguments begin on page 13 of this paper.